

PCN# 20230228003.1 Qualification of new Fab site (RFAB) using qualified Process Technology, Die Revision, Datasheet update for select devices Change Notification / Sample Request

Date: March 30, 2023 To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments (TI). The details of this change are on the following pages, and are in alignment with our standard product change notification (PCN) <u>process</u>.

TI requires acknowledgement of receipt of this notification within 30 days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within 30 days of this notification, given that samples are not built ahead of the change.

The Proposed First Ship date in this PCN letter is the earliest possible date that customers could receive the changed material. It is our commitment that the changed device will not ship before that date. If samples are requested within the 30 day sample request window, customers will still have 30-days to complete their evaluation regardless of the proposed 1st ship date.

This particular PCN is related to TI's multiyear transition plan for our two remaining factories with 150-millimeter production (DFAB in Dallas, Texas, and SFAB in Sherman, Texas). DFAB will remain open, but will focus on 200-mm production, with a smaller set of technologies. SFAB will close no earlier than 2024 and no later than 2025. As referenced in the "reason for change" below, these changes are part of our multiyear plan to transition these products to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (<u>PCN ww admin team@list.ti.com</u>). For sample requests or sample related questions, contact your local Field Sales Representative. As always, we thank you for your continued business.

PCN Team SC Business Services

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
CD4052BPWR	null
CD4051BPWR	null
CD4053BPWR	null

Technical details of this Product Change follow on the next page(s).

					230228003.1			N Da	ite:	March 30, 2023
Titl	0.	Qualification of	of ne	ew Fa	b site (RFAB) using c	qualified	1 Pro	ocess	5 Techr	nology, Die Revision,
Title: Datasheet update for select devices										
Cus	stomer	Contact:		PCN	<u>Manager</u>		De	pt:		Quality Services
Proposed 1 st Ship Date:					ple requests cepted until:			April 30, 2023*		
*Sample requests received after April 30, 2023 will not be supported.										
Cha	ange Ty	vpe:								
	Assem	Assembly Site 🗌 Asse		Assembly Process	Asse			Asse	mbly Materials	
\boxtimes	Design	า		\square	Electrical Specificat	ion			Mechanical Specification	
	Test S	ite		\square	Packing/Shipping/Labeling				Test Process	
	Wafer	Bump Site		Wafer Bump Material			🗌 🗌 Wafe		er Bump Process	
\boxtimes	Wafer	Fab Site		\square	Wafer Fab Materials			\boxtimes	Wafe	r Fab Process
					Part number change					
1										

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (RFAB, LBC9) options for selected devices as listed below in the product affected section.

	Current Fab	Site		New Fab S	Site		
Fab Site	Process	Wafer Diameter	Fab Site	Process	Wafer Diameter		
SFAB	CD4000	150 mm	RFAB	LBC9	300 mm		

The die was also changed as a result of the process change.

The datasheet will be changing as a result of the above mentioned changes. The datasheet change details can be reviewed in the datasheet revision history. The link to the revised datasheets are available in the table below.

INSTRUMENTS		SCHS047K - AUGUST 1998 - RE	USED MARCH 202
Changes from Revision J (February 202	3) to Revision K (March	h 2023)	Page
Added PW package information through	nout the data sheet		1
Texas Instruments		CD4051B, CD40	
INSTRUMENTS		SCHS047J – AUGUST 1998 – REVISE	D FEBRUARY 2023
Changes from Revision I (September 20	17) to Revision J (Febr	ruary 2023)	Page
Updated the numbering format for table	s, figures, and cross-refe	erences throughout the docume	ent1
Updated the Inhibit-to-Signal OUT (Cha			
Updated the values in the ESD Ratings	section		
Updated the Quiescent Device Current,			
Updated the OFF Channel Leakage Cu	rrent: Any Channel OFF	(Max) or ALL Channels OFF (C	Common
OUT/IN) (Max) typical values			
Updated the ON Channel Leakage Cur			
(Max) maximum values			6
Updated the Input Low Voltage, VIL, Ma	ax values		6
Updated the Input Current, IIN (Max) ty			
	nnel Turning OFF) typic:	al values	6
Updated the Inhibit-to-Signal OUT (Cha			
Updated the Inhibit-to-Signal OUT (Cha Updated the Typical Characteristics see			

Product Folder	Current Datasheet Number	New Datasheet Number	Link to full datasheet
CD405xB	SCHS047I	SCHS047K	http://www.ti.com/product/CD4051B

Tube, G3 and G4 versions of the devices are included in EOL notice PDN# 20230228005.3.

Qual details are provided in the Qual Data Section.

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
SH-BIP-1	SHE	USA	Sherman
RFAB	RFB	USA	Richardson

Die Rev:

Current	New
Die Rev [2P]	Die Rev [2P]
A, -	В

Sample product shipping label (not actual product label):

TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 20: MSL '2 /260C/1 YEAR SEAL MSL 1 /235C/UNLIM 03/29 OPT: 39 LBL: 5A (L)T0:175	оч рт /04	1P) SN74LS07NSR (Q) 2000 (D) 0336 31T)LOT: 3959047MLA 4W) TKY (1T) 7523483S P) 2P) REV: (V) 009991 2D) REV: (V) 009991 2D) CS0: SHE (21L) CC0:US 22L) AS0: MLA (23L) ACO: MY	A
Product Affected:			
CD4051BPWR	CD4052BPWR	CD4053BPWR	

For alternate parts with similar or improved performance, please visit the product page on $\underline{\text{TI.com}}$

Qualification Report

Approve Date 05-January-2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: CD4051BPWR	Qual Device: CD4052BPWR	Qual Device: <u>CD4053BPWR</u>	QBS Reference: TCA6408AQPWRQ1	QBS Reference: <u>TMUX4051PWR</u>	QBS Reference: <u>TMUX4052PWR</u>	QBS Reference: <u>TMUX4053PWR</u>	QBS Reference: <u>TMUX4051PWR</u>	QBS Reference: TMUX4053PWR
HAST	A2	Biased HAST	130C	96 Hours	-	-	-	3/231/0	-	-	-	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-	-	-	-
тс	A4	Temperature Cycle	-65/150C	500 Cycles	-	-	-	3/231/0	-	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/45/0	-	-	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	1/77/0	-	-	-	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	-	1/76/0	-	1/76/0	-	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	-	1/76/0	-	1/76/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	3/30/0	-	-	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	-	-	-	1/3/0	-	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0		1/3/0	-	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	1000 Volts	1/3/0		1/3/0		1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	4000 Volts	-		-	1/3/0	-	-	-		
LU	E4	Latch-Up	Per JESD78	-	1/3/0		1/3/0	1/6/0	1/3/0	-	-		1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/5/0	-	1/30/0	1/30/0	-	1/30/0	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-		-	3/90/0	-	-	-	-	-

QBS: Qual By Similarity

Qual Device CD4051BPWR is qualified at MSL1 260C
Qual Device CD4052BPWR is qualified at MSL1 260C

Qual Device CD4053BPWR is gualified at MSL1 260C

 Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contact shown below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	<u>PCN ww admin team@list.ti.com</u>

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